

<b>L Numb r</b>	<b>Hits</b>	<b>Sear h T xt</b>	<b>DB</b>	<b>Tim stamp</b>
<b>1</b>	<b>64</b>	<b>(s rializer des rializer SERDES).ab. and (cl ck cl cking CLK) and (t st testing test d t ster)</b>	<b>USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB</b>	<b>2004/02/04 15:55</b>
<b>2</b>	<b>6</b>	<b>(serializer deserializer SERDES).ab. and (clock clocking CLK) and (test testing tested tester) and (test adj pattern)</b>	<b>USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB</b>	<b>2004/02/04 19:46</b>
<b>3</b>	<b>88</b>	<b>(serializer deserializer SERDES) and (clock clocking CLK) and (test testing tested tester) and (test adj pattern)</b>	<b>USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB</b>	<b>2004/02/04 16:07</b>
<b>4</b>	<b>36</b>	<b>(serializer deserializer SERDES) and (clock clocking CLK) and (test testing tested tester) and (test adj pattern) and (test with (serializer deserializer SERDES))</b>	<b>USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB</b>	<b>2004/02/04 15:56</b>
<b>5</b>	<b>36</b>	<b>(serializer deserializer SERDES or serializer?deserializer) and (clock clocking CLK) and (test testing tested tester) and (test adj pattern) and (test with (serializer deserializer SERDES))</b>	<b>USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB</b>	<b>2004/02/04 15:57</b>
<b>6</b>	<b>36</b>	<b>(serializer deserializer SERDES or serializer?deserializer) and (clock clocking CLK) and (test testing tested tester) and (test adj pattern) and (test with (serializer deserializer serializer?deserializer SERDES))</b>	<b>USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB</b>	<b>2004/02/04 15:57</b>
<b>7</b>	<b>3</b>	<b>(serializer deserializer SERDES or serializer?deserializer) and (clock clocking CLK) and (test testing tested tester) and (test adj pattern) and (test with (serializer deserializer serializer?deserializer SERDES)) and fpga</b>	<b>USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB</b>	<b>2004/02/04 15:57</b>
<b>8</b>	<b>16</b>	<b>(serializer?deserializer SERDES) and (clock clocking CLK) and (test testing tested tester) and (test adj pattern)</b>	<b>USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB</b>	<b>2004/02/04 16:07</b>
<b>11</b>	<b>3</b>	<b>("5424655"   "5737235"   "5825201").PN.</b>	<b>USPAT</b>	<b>2004/02/04 16:11</b>
<b>14</b>	<b>0</b>	<b>6617877.URPN.</b>	<b>USPAT</b>	<b>2004/02/04 16:12</b>
<b>15</b>	<b>0</b>	<b>6617877.URPN.</b>	<b>USPAT</b>	<b>2004/02/04 16:12</b>
<b>16</b>	<b>0</b>	<b>6542096.URPN.</b>	<b>USPAT</b>	<b>2004/02/04 16:33</b>

17	3	("5424655"   "5737235"   "5825201").PN.	USPAT	2004/02/04 16:35
18	0	6542096.URPN.	USPAT	2004/02/04 16:38
19	0	6542096.URPN.	USPAT	2004/02/04 16:38
20	0	6617877.URPN.	USPAT	2004/02/04 16:40
21	21	("5361373" "5537601" "5652904" "5671355" "5752035" "5970254" "6020755" "6096091" "6279045" "6282627" "6343207").pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/04 16:43
22	11	("5361373" "5537601" "5652904" "5671355" "5752035" "5970254" "6020755" "6096091" "6279045" "6282627" "6343207").pn.	USPAT	2004/02/04 16:43
33	517	fpga and Jitter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/04 19:49
34	6	(fpga and Jitter).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/04 19:52
35	1	6295315.pn.	USPAT	2004/02/04 19:52
-	2579	FPGA.ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/03 18:19
-	346	(serializer deserializer).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/04 11:12
-	4	FPGA.ab. and ((serializer deserializer).ab.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/03 18:24
-	11	34363.pn. 5914616.pn. 5844829.pn. 6232845.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/03 18:25
-	8	("5790563" "5793822" "6003150" "6191614").pn.	USPAT; US-P PUB; EP ; JPO; DERWENT; IBM_TDB	2004/02/04 10:14

-	50	("5550843" "5675589" "5841790" "5844917" "5878051" "5237219" "5426738" "5426741" "5430687" "5508636" "5619513" "5651013" "5720031" "5732246" "5781756" "5848026" "5867507" "6021513" "6049487" "6134677" "6137738" "6150863" "6167001" "6173424" "6307877" "6321366" "6330693" "6331790" "6389379" "6421251" "6430088" "6436741" "6601218" "6631487" "5465261" "6141775" "6237021" "6239611" "5309428" "5363366" "5365513" "5381348" "5425017" "5444695" "5479355" "5633813" "5737693" "5841967" "5887244" "5898905").pn.	USPAT; US-PGPUB	2004/02/03 18:44
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-	0	("5550843" "5675589" "5841790" "5844917" "5878051" "5237219" "5426738" "5426741" "5430687" "5508636" "5619513" "5651013" "5720031" "5732246" "5781756" "5848026" "5867507" "6021513" "6049487" "6134677" "6137738" "6150863" "6167001" "6173424" "6307877" "6321366" "6330693" "6331790" "6389379" "6421251" "6430088" "6436741" "6601218" "6631487" "5465261" "6141775" "6237021" "6239611" "5309428" "5363366" "5365513" "5381348" "5425017" "5444695" "5479355" "5633813" "5737693" "5841967" "5887244" "5898905").pn. ) and ("5790563" "5793822" "6003150" "6191614").pn.)	USPAT; US-PGPUB; EP ; JP ; DERWENT; IBM_TDB	2004/02/03 18:29
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-	0	("5550843" "5675589" "5841790" "5844917" "5878051" "5237219" "5426738" "5426741" "5430687" "5508636" "5619513" "5651013" "5720031" "5732246" "5781756" "5848026" "5867507" "6021513" "6049487" "6134677" "6137738" "6150863" "6167001" "6173424" "6307877" "6321366" "6330693" "6331790" "6389379" "6421251" "6430088" "6436741" "6601218" "6631487" "5465261" "6141775" "6237021" "6239611" "5309428" "5363366" "5365513" "5381348" "5425017" "5444695" "5479355" "5633813" "5737693" "5841967" "5887244" "5898905").pn. ) and (34363.pn. 5914616.pn. 5844829.pn. 6232845.pn.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/03 18:29
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-	0	("5550843" "5675589" "5841790" "5844917" "5878051" "5237219" "5426738" "5426741" "5430687" "5508636" "5619513" "5651013" "5720031" "5732246" "5781756" "5848026" "5867507" "6021513" "6049487" "6134677" "6137738" "6150863" "6167001" "6173424" "6307877" "6321366" "6330693" "6331790" "6389379" "6421251" "6430088" "6436741" "6601218" "6631487" "5465261" "6141775" "6237021" "6239611" "5309428" "5363366" "5365513" "5381348" "5425017" "5444695" "5479355" "5633813" "5737693" "5841967" "5887244" "5898905").pn. ) and (FP A.ab. and ((s rializer deserializer).ab.))	USPAT; US-PGPUB; EP ; JPO; DERWENT; IBM_TDB	2004/02/03 18:29
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-	0	((serializ r deserializ r).ab.) and (("5550843" "5675589" "5841790" "5844917" "5878051" "5237219" "5426738" "5426741" "5430687" "5508636" "5619513" "5651013" "5720031" "5732246" "5781756" "5848026" "5867507" "6021513" "6049487" "6134677" "6137738" "6150863" "6167001" "6173424" "6307877" "6321366" "6330693" "6331790" "6389379" "6421251" "6430088" "6436741" "6601218" "6631487" "5465261" "6141775" "6237021" "6239611" "5309428" "5363366" "5365513" "5381348" "5425017" "5444695" "5479355" "5633813" "5737693" "5841967" "5887244" "5898905").pn. )	USPAT; US-P PUB; EPO; JP ; DERWENT; IBM_TDB	2004/02/03 18:52
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-	28971	((gate adj array) FP A)	USPAT; US-P PUB; EP ; JPO; DERWENT; IBM_TDB	2004/02/03 18:54
-	7207	((gate adj array) FPGA).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/03 18:56
-	47	((gate adj array) FPGA).ab. and crc	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/03 19:03

-	49	("5550843" "5675589" "5841790" "5844917" "5878051" "5237219" "5426738" "5426741" "5430687" "5508636" "5619513" "5651013" "5720031" "5732246" "5781756" "5848026" "5867507" "6021513" "6049487" "6134677" "6137738" "6150863" "6167001" "6173424" "6307877" "6321366" "6330693" "6331790" "6389379" "6421251" "6430088" "6436741" "6601218" "6631487" "5465261" "6141775" "6237021" "6239611" "5309428" "5363366" "5365513" "5381348" "5425017" "5444695" "5479355" "5633813" "5737693" "5841967" "5887244" "5898905").pn. and fpga	USPAT; US-PGPUB	2004/02/03 19:03
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-	8	"912683"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/04 11:12
-	366	(s rializ r d s rializer SERDES).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/04 15:44
-	8	(serializer deserializer SERDES).ab. and (FPGA (gate adj array) PGA).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/04 16:41

09912683\_CLS  
Most Frequently Occurring Classifications of Patents Returned  
From A Search of 09912683 on October 28, 2003

Original Classifications

3	326/38
3	370/245
3	455/67.14
3	703/14
3	714/42
3	714/724
3	714/726
2	365/189.04
2	714/30

Cross-Reference Classifications

4	714/717
4	714/725
3	326/38
3	326/41
3	370/452
3	714/733
3	716/16
3	716/4
2	257/E23.124
2	257/E23.125
2	365/189.04
2	365/230.05
2	455/423
2	714/25
2	714/734

Combined Classifications

6	326/38
5	714/725
4	326/41
4	365/189.04
4	370/452
4	703/14
4	714/717
4	714/724
4	716/16
3	370/245
3	455/67.14
3	714/42
3	714/726
3	714/733
3	716/4

09912683\_CLS

2 257/E23.124  
2 257/E23.125  
2 326/16  
2 365/201  
2 365/230.05  
2 365/230.08  
2 455/423  
2 714/25  
2 714/30  
2 714/718  
2 714/731  
2 714/734  
2 716/6

09912683\_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09912683 on October 28, 2003

- 6 326/38 (3 OR, 3 XR)
  - Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
  - 326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G., UNIVERSAL, ETC.)
  - 326/38 .Having details of setting or programming of interconnections or logic functions
  
- 5 714/725 (1 OR, 4 XR)
  - Class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
  - 714/699 PULSE OR DATA ERROR HANDLING
  - 714/724 .Digital logic testing
  - 714/725 ..Programmable logic array (PLA) testing
  
- 4 326/41 (1 OR, 3 XR)
  - Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
  - 326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G., UNIVERSAL, ETC.)
  - 326/39 .Array (e.g., PLA, PAL, PLD, etc.)
  - 326/41 ..Significant integrated structure, layout, or layout interconnections
  
- 4 365/189.04 (2 OR, 2 XR)
  - Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
  - 365/189.01 READ/WRITE CIRCUIT
  - 365/189.04 .Simultaneous operations (e.g., read/write)
  
- 4 370/452 (1 OR, 3 XR)
  - Class 370 : MULTIPLEX COMMUNICATIONS
  - 370/431 CHANNEL ASSIGNMENT TECHNIQUES
  - 370/449 .Polling
  - 370/450 ..Passing a signal identifying the idle or bus state of a channel (e.g., token passing)
  - 370/451 ...On bus
  - 370/452 ....On ring or loop
  
- 4 703/14 (3 OR, 1 XR)
  - Class 703 : DATA PROCESSING: STRUCTURAL DESIGN, MODELING, SIMULATION, AND EMULATION
  - 703/13 SIMULATING ELECTRONIC DEVICE OR ELECTRICAL SYSTEM
  - 703/14 .Circuit simulation

# 09912683\_CLSTITLES

- 4 714/717 (0 OR, 4 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/712 .Transmission facility testing  
 714/717 ..Loop or ring configuration
- 4 714/724 (3 OR, 1 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing
- 4 716/16 (1 OR, 3 XR)  
 Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
 CIRCUIT OR SEMICONDUCTOR MASK  
 716/1 CIRCUIT DESIGN  
 716/12 .Routing (e.g., routing map, netlisting)  
 716/16 ..PLA, PLD, FPGA, OR MCM
- 3 370/245 (3 OR, 0 XR)  
 Class 370 : MULTIPLEX COMMUNICATIONS  
 370/241 DIAGNOSTIC TESTING (OTHER THAN SYNCHRONIZATION  
 )  
 370/242 .Fault detection  
 370/245 ..Of a local area network
- 3 455/67.14 (3 OR, 0 XR)  
 Class 455 : TELECOMMUNICATIONS  
 455/39 TRANSMITTER AND RECEIVER AT SEPARATE STATIONS  
 455/67.11 .Having measuring, testing, or monitoring of  
 system or part  
 455/67.14 ..Using a test signal
- 3 714/42 (3 OR, 0 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
 714/1 .Reliability and availability  
 714/25 ..Fault locating (i.e., diagnosis or testing)  
 714/40 ...Component dependent technique  
 714/42 ....Memory or storage device component fault

09912683\_CLSTITLES

3 714/726 (3 OR, 0 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/726 ..Scan path testing (e.g., level sensitive sca  
 n  
 design (LSSD))

3 714/733 (0 OR, 3 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/733 ..Built-in testing circuit (BILBO)

3 716/4 (0 OR, 3 XR)  
 Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
 CIRCUIT OR SEMICONDUCTOR MASK  
 716/1 CIRCUIT DESIGN  
 716/4 .Testing or evaluating

2 257/E23.124 (0 OR, 2 XR)  
 Class 257 : ACTIVE SOLID-STATE DEVICES  
 257/E23.113 ....Ceramic materials or glass (EPO)  
 257/E23.116 .Encapsulations, e.g., encapsulating layers,  
 coatings, e.g., for protection (EPO)  
 257/E23.123 ..Characterized by arrangement or shape (EPO)  
 257/E23.124 ...Device being completely enclosed (EPO)

2 257/E23.125 (0 OR, 2 XR)  
 Class 257 : ACTIVE SOLID-STATE DEVICES  
 257/E23.113 ....Ceramic materials or glass (EPO)  
 257/E23.116 .Encapsulations, e.g., encapsulating layers,  
 coatings, e.g., for protection (EPO)  
 257/E23.123 ..Characterized by arrangement or shape (EPO)  
 257/E23.124 ...Device being completely enclosed (EPO)  
 257/E23.125 ....Substrate forming part of encapsulation  
 (EPO)

2 326/16 (1 OR, 1 XR)  
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY  
 326/16 WITH TEST FACILITATING FEATURE

2 365/201 (1 OR, 1 XR)  
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL

09912683\_CLSTITLES  
 365/189.01 READ/WRITE CIRCUIT  
 365/201 .Testing

2 365/230.05 (0 OR, 2 XR)  
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
 365/230.01 ADDRESSING  
 365/230.05 .Multiple port access

2 365/230.08 (1 OR, 1 XR)  
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
 365/230.01 ADDRESSING  
 365/230.08 .Including particular address buffer or latch  
 circuit arrangement

2 455/423 (0 OR, 2 XR)  
 Class 455 : TELECOMMUNICATIONS  
 455/403 RADIOTELEPHONE SYSTEM  
 455/422.1 .Zoned or cellular telephone system  
 455/423 ..Diagnostic testing, malfunction indication,  
 or electrical condition measurement

2 714/25 (0 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
 714/1 .Reliability and availability  
 714/25 ..Fault locating (i.e., diagnosis or testing)

2 714/30 (2 OR, 0 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
 714/1 .Reliability and availability  
 714/25 ..Fault locating (i.e., diagnosis or testing)  
 714/27 ...Particular access structure  
 714/30 ....Built-in hardware for diagnosing or testin

g  
 or test mode  
 within-system component (e.g., microprocess  
 circuit, scan path)

2 714/718 (1 OR, 1 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY

09912683\_CLSTITLES

714/699 PULSE OR DATA ERROR HANDLING  
714/718 .Memory testing

2 714/731 (1 OR, 1 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/726 ..Scan path testing (e.g., level sensitive sca

n

design (LSSD))

714/731 ...Clock or synchronization

2 714/734 (0 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/734 ..Structural (in-circuit test)

2 716/6 (1 OR, 1 XR)

Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
CIRCUIT OR SEMICONDUCTOR MASK

716/1 CIRCUIT DESIGN

716/4 .Testing or evaluating

716/5 ..Design verification (e.g., wiring line  
capacitance, fan-out checking, minimum pat

h width)

716/6 ...Timing analysis (e.g., delay time, path  
delay, latch timing)

09912683\_LIST

PLUS Search Results for S/N 09912683, Searched October 28, 2003

5550843  
5675589  
5841790  
5844917  
5878051  
5237219  
5426738  
5426741  
5430687  
5508636  
5619513  
5651013  
5720031  
5732246  
5781756  
5848026  
5867507  
6021513  
6049487  
6134677  
6137738  
6150863  
6167001  
6173424  
6307877  
6321366  
6330693  
6331790  
6389379  
6421251  
6430088  
6436741  
6601218  
6631487  
5465261  
6141775  
6237021  
6239611  
5309428  
5363366  
5365513  
5381348  
5425017  
5444695  
5479355  
5633813

09912683\_LIST

5737693  
5841967  
5887244  
5898905

09912683\_QUAL

5550843 62  
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5844917 62  
5878051 62  
5237219 62  
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5426741 62  
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5781756 62  
5848026 62  
5867507 62  
6021513 62  
6049487 62  
6134677 62  
6137738 62  
6150863 62  
6167001 62  
6173424 62  
6307877 62  
6321366 62  
6330693 62  
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6421251 62  
6430088 62  
6436741 62  
6601218 62  
6631487 62  
5465261 60  
6141775 51  
6237021 51  
6239611 51  
5309428 51  
5363366 51  
5365513 51  
5381348 51  
5425017 51  
5444695 51  
5479355 51  
5633813 51  
5737693 51  
5841967 51

09912683\_QUAL

5887244 51  
5898905 51